

# Determination of Cr diffusivity in pure Ni and Ni-20Cr alloy

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 $\rightarrow$  4.2 Characterisation of cold work effects on microstructure

Objective is to understand the Cr depletion depth observed at low temperatures in oxidized cracks formed by stress corrosion cracking in PWR: extrapolation made from high temperature measurements of Cr diffusivity cannot explain it. However if diffusion coefficients are higher at low temperature (as data obtained by Chetriou *et al*), the Cr depletion depth could be explained

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 $\rightarrow$  Need of Cr diffusion coefficient at low temperature



### Content



- 1. In volume
  - Cr in Ni
  - <sup>54</sup>Cr in Ni-20Cr
- 2. In grain boundaries (Cr in Ni)
  - Annealed samples, regimes B and C
  - Rolled samples

### Method



Experimental protocole:

- rolling-recristallization of the substrat (Ni/Ni-20Cr)
- Mechanical grinding until 1 μm
- Thin deposit (5 nm) of natural Cr (for diffusion in pure Ni)/<sup>54</sup>Cr (for diffusion in Ni-20Cr) by sublimation
- Ageing in glass ampoule under vaccuum, with Zr chips
- Concentration profile measured by SIMS
- Abrasion depth is then measured by contact profilometric method

Depth profile of a SIMS crater

SIMS Analyses :  $\bigotimes$  8-60 µm  $\rightarrow$  measure performed within one grain or for one single grain boundary

#### Ni rolled-recristallized





# **1. Volume diffusion**: temperature / time conditions for ageing



Conditions:

- Characteristic diffusion depth > 100 nm small enough for having SIMS flat floor crater and deep enough for having enough points for good fit
- Ageing time has to be much higher (10 times) than the incompressible heating/cooling time (5 min) and reasonable (one year at maximum)



# **1. Volume diffusion**: results treatments





# **1. Volume diffusion**: results for Cr in Ni





- Very good agreement with extrapolation at low temperatures of measurements made at high temperatures → no accelerated diffusion at low temperature
- These results cannot explain the higher Cr depletion depth observed during oxidation in PWR

## **1. Volume diffusion**: results for Cr in Ni-20Cr





Very good agreement with extrapolation at low temperatures of measurements made at high temperatures

#### **1. Volume diffusion**: all data for Cr in Ni alloys and pure Ni





- Our results in agreement with data measured at high temperatures
- *D*<sub>Cr\*</sub> is similar in Ni, Ni-Cr, Ni-Fe-Cr, Fe-Ni-Cr → model alloys are good candidates for measurement of Cr diffusivities in FCC Ni-Fe-Cr alloys

# Grain boundary diffusion: temperature / time conditions for ageing → only Cr in Ni

Conditions:

- For B regime  $\delta < 10\sqrt{D_{\rm v}t}$  and for C regime  $\delta > 10\sqrt{D_{\rm v}t}$
- Ageing time has to be much higher than the incompressible heating/cooling time (5 min)







*I. Kaur, Y. Mishin, W. Gust, Fundamentals of Grain and Interphase Boundary Diffusion, 1995 H. Mehrer, Diffusion in Solids, 2007* 

**2. Grain boundary diffusion**: Regime B SIMS profiles



Ageing: 28 h at 563 °C



#### **2. Grain boundary diffusion**: Regime B 90% rolled Ni





Positive slope

#### During diffusion step $\rightarrow$ fast recristallization

Optical image of the crater floor



#### **2. Grain boundary diffusion**: Regime C SIMS profiles





# **2. Grain boundary diffusion**: all results





- Intergranular Diffusivity very scattered → due to various GB misorientation?
   Statistics could be done
- Trend in agreement with data obtained at high temperature
- No effect of cold-work & recrystallization on Cr diffusion

### 3. Summary





3 orders of magnitudes between diffusion in grain boundaries and in volume  $\rightarrow$  order of magnitudes frequently obtained

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### 4. Conclusions and prospects



Tracer Diffusion In volume

- D<sup>Ni</sup><sub>Cr\*</sub> measured until 542 °C (versus 950 °C before)
- *Q* constant between 1400 and 542 °C
- Lower temperatures: need a surface cleaning before Cr deposit, and SIMS profile for very small depth (SIMS until 50 nm, Tomographic Atom Probe for lower?)
- $D_{Cr^*}$  is very similar for Ni, Ni-Cr, Ni-Fe-Cr, Fe-Ni-Cr

In grain boundaries

- Measurements of *D*<sup>Ni</sup><sub>Cr\*</sub> performed until 346 °C
- Very complicated
- $D_{Cr^*}^{Ni-20Cr}$  impossible due to high level (2.365 at %) of <sup>54</sup>Cr within natural Cr
- Obtained results in agreement with data measured at high temperatures → no accelerated diffusion at low temperature
- Cr diffusion is not increased in rolled samples → no accelerated diffusion due to cold-work

### 4. Conclusions and prospects

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This study cannot explain the higher Cr depletion depth observed in oxidized cracks formed by stress corrosion cracking in PWR

- Is it due to combine effect of diffusion and stress?
   →Cr tracer diffusion coefficient could be measured under creep test (will be done in other project)
- Is it due to combine effect of diffusion and oxidation? Vacancies created in alloy by oxidation could accelerate the Cr diffusion

   → oxidation tests with sample of various microstructures are conducted in gas environments firstly and in PWR conditions secondly → in progress

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